

March 2010

FDZ372NZ

Features

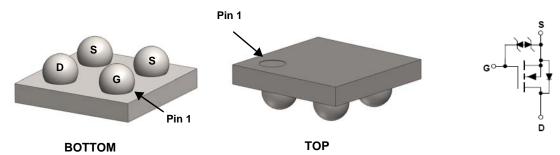
- Max $r_{DS(on)} = 50 \text{ m}\Omega$ at $V_{GS} = 4.5 \text{ V}$, $I_D = 2 \text{ A}$
- Max $r_{DS(on)}$ = 60 m Ω at V_{GS} = 2.5 V, I_D = 2 A
- Max $r_{DS(on)} = 72 \text{ m}\Omega$ at $V_{GS} = 1.8 \text{ V}$, $I_D = 1 \text{ A}$
- Max $r_{DS(on)} = 93 \text{ m}\Omega$ at $V_{GS} = 1.5 \text{ V}$, $I_D = 1 \text{ A}$
- Occupies only 1.0 mm² of PCB area. Less than 30% of the area of 2x2 BGA
- Ultra-thin package: less than 0.4 mm height when mounted to PCB
- HBM ESD protection level > 3200V (Note3)
- RoHS Compliant

General Description

Designed on Fairchild's advanced 1.5 V PowerTrench[®] process with state of the art "fine pitch" **Thin** WLCSP packaging process, the FDZ372NZ minimizes both PCB space and $r_{DS(on)}$. This advanced WLCSP MOSFET embodies a breakthrough in packaging technology which enables the device to combine excellent thermal transfer characteristics, ultra-low profile packaging, low gate charge, and low $r_{DS(on)}$.

Applications

- Battery management
- Load switch
- Battery protection



WL-CSP 1.0X1.0 Thin

MOSFET Maximum Ratings T_A = 25 °C unless otherwise noted

Symbol	Par	Parameter			
V_{DS}	Drain to Source Voltage			20	V
V_{GS}	Gate to Source Voltage			±8	V
1	Drain Current -Continuous	T _A = 25 °C	(Note 1a)	4.7	۸
'D	-Pulsed			12	A
В	Power Dissipation	T _A = 25 °C	(Note 1a)	1.7	W
P_{D}	Power Dissipation	T _A = 25 °C	(Note 1b)	0.5	VV
T _J , T _{STG}	Operating and Storage Junction Temp	Operating and Storage Junction Temperature Range			°C

Thermal Characteristics

$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	(Note 1a)	75	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	(Note 1b)	260	C/VV

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
L	FDZ372NZ	WL-CSP 1.0x1.0 Thin	7 "	8 mm	5000 units

Electrical Characteristics T_J = 25 °C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	cteristics					
BV _{DSS}	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	20			V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	I_D = 250 μ A, referenced to 25 °C		18		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 16 V, V _{GS} = 0 V			1	μΑ
I _{GSS}	Gate to Source Leakage Current	$V_{GS} = \pm 8 \text{ V}, V_{DS} = 0 \text{ V}$			±10	μΑ

On Characteristics

V _{GS(th)}	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250 \mu A$	0.4	0.7	1	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	I_D = 250 μ A, referenced to 25 °C		-3		mV/°C
		$V_{GS} = 4.5 \text{ V}, I_D = 2 \text{ A}$		40	50	
	$V_{GS} = 2.5 \text{ V}, I_D = 2 \text{ A}$		45	60		
r _{DS(on)}	Drain to Source On Resistance	$V_{GS} = 1.8 \text{ V}, I_D = 1 \text{ A}$		53	72	mΩ
		$V_{GS} = 1.5 \text{ V}, I_D = 1 \text{ A}$		63	93	
		$V_{GS} = 4.5V$, $I_D = 2 A$, $T_J = 125$ °C		57	81	
9 _{FS}	Forward Transconductance	$V_{DS} = 5 \text{ V}, I_{D} = 4.7 \text{ A}$		22		S

Dynamic Characteristics

C _{iss}	Input Capacitance	V 40.V.V 0.V	515	685	pF
C _{oss}	Output Capacitance	V _{DS} = 10 V, V _{GS} = 0 V, f = 1 MHz	85	115	pF
C _{rss}	Reverse Transfer Capacitance	1 - 1 1011 12	65	100	pF

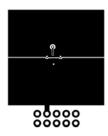
Switching Characteristics

t _{d(on)}	Turn-On Delay Time		6.2	12	ns
t _r	Rise Time	V _{DD} = 10 V, I _D = 4.7 A	3.6	10	ns
t _{d(off)}	Turn-Off Delay Time	$V_{GS} = 4.5 \text{ V}, R_{GEN} = 6 \Omega$	26	42	ns
t _f	Fall Time		5.6	12	ns
Q_g	Total Gate Charge	V 45VV 40V	7	9.8	nC
Q_{gs}	Gate to Source Gate Charge	$V_{GS} = 4.5 \text{ V}, V_{DD} = 10 \text{ V}$ 	8.0		nC
Q_{gd}	Gate to Drain "Miller" Charge	ID - 4.1 V	1.6		nC

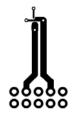
Drain-Source Diode Characteristics

V_{SD}	Source to Drain Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = 1.4 \text{ A}$ (Note 2)	0.7	1.2	V
t _{rr}	Reverse Recovery Time	I _F = 4.7 A, di/dt = 100 A/μs	11	20	ns
Q _{rr}	Reverse Recovery Charge	1F = 4.7 A, αι/αι = 100 A/μS	2.6	10	nC

^{1.} R_{0,1A} is determined with the device mounted on a 1 in² pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. R_{0,1C} is guaranteed by design while R_{0,1C} is determined by the user's board design.



a. 75 °C/W when mounted on a 1 in² pad of 2 oz copper.



b. 260 °C/W when mounted on a minimum pad of 2 oz copper.

- 2. Pulse Test: Pulse Width < $300\mu\text{s},$ Duty cycle < 2.0%.
- 3. The diode connected between the gate and source serves only as protection ESD. No gate overvoltage rating is implied.

Typical Characteristics T_J = 25 °C unless otherwise noted

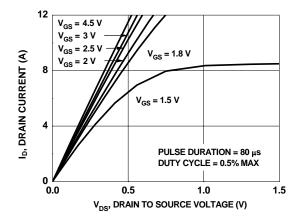


Figure 1. On-Region Characteristics

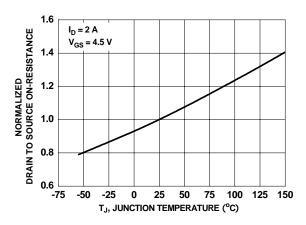


Figure 3. Normalized On-Resistance vs Junction Temperature

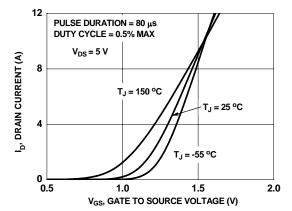


Figure 5. Transfer Characteristics

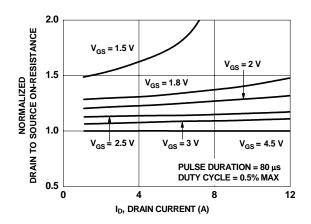


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

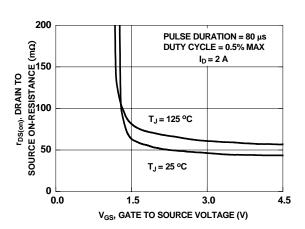


Figure 4. On-Resistance vs Gate to Source Voltage

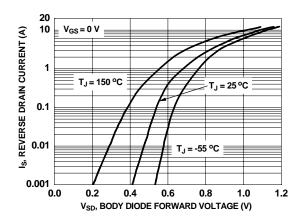


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

Typical Characteristics T_J = 25 °C unless otherwise noted

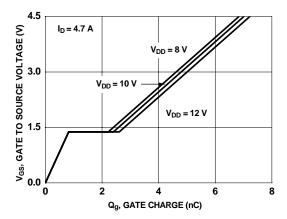


Figure 7. Gate Charge Characteristics

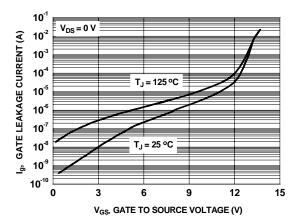


Figure 9. Gate Leakage Current vs Gate to Source Voltage

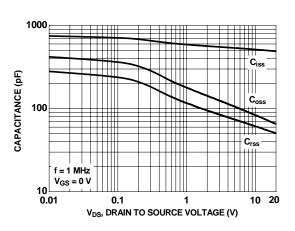


Figure 8. Capacitance vs Drain to Source Voltage

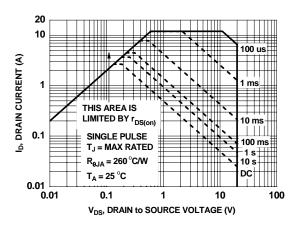


Figure 10. Forward Bias Safe Operating Area

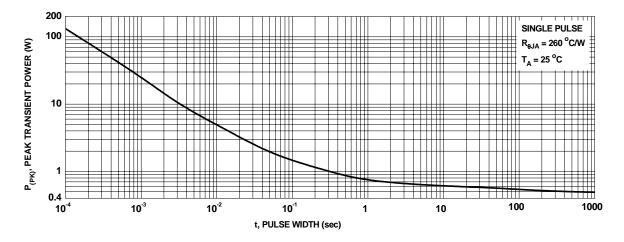


Figure 11. Single Pulse Maximum Power Dissipation

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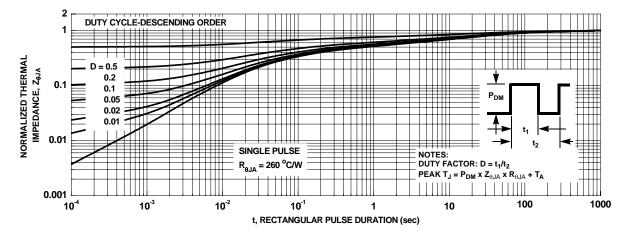
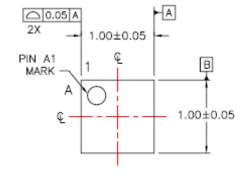
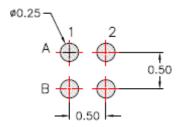


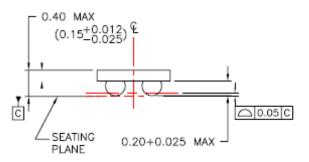
Figure 12. Junction-to-Ambient Transient Thermal Response Curve

Dimensional Outline and Pad Layout





△0.05B 2X



LAND PATTERN RECOMMENDATION



PIN A1 © B 0.50 (HIDDEN) A 1 2 - 0.50

NOTES: UNLESS OTHERWISE SPECIFIED

- A) THIS PACKAGE IS NOT PRESENTLY REGISTERED WITH ANY STANDARDS COMMITTEE.
- B) DIMENSIONS ARE IN MILLIMETERS.
- C) DRAWING CONFORMS TO ASME Y14.5M-1994
- D) TERMINAL CONFIGURATION TABLE:

GATE	SOURCE	DRAIN
A1	A2, B2	В

E) DRAWING FILENAME: PRELIMINARY





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